

1 pC Charge Injection, 100 pA Leakage, CMOS, ±5 V/5 V/3 V, Quad SPST Switches

Enhanced Product ADG613-EP

FEATURES

1 pC charge injection
±0.1 nA maximum at 25°C leakage currents
85 Ω on resistance
Rail-to-rail switching operation
Fast switching times
16-lead TSSOP
Typical power consumption: ≤11 nW
TTL-/CMOS-compatible inputs
V_{SS} to V_{DD} analog signal range
±2.7 V to ±5.5 V dual supply operation
2.7 V to 5.5 V single-supply operation

ENHANCED PRODUCT FEATURES

Fully specified at ±5 V, 3 V, and 5 V

Supports defense and aerospace applications (AQEC standard)
Military temperature range: -55°C to+125°C
Controlled manufacturing baseline
1 assembly site
1 test site
1 fabrication site
Enhanced product change notification
Qualification data available on request

APPLICATIONS

Automatic test equipment
Data acquisition systems
Battery-powered systems
Communications systems
Sample-and-hold systems
Audio signal routing
Relay replacement
Avionics

GENERAL DESCRIPTION

The ADG613-EP is a monolithic CMOS device containing four independently selectable switches. This switch offers ultralow charge injection of 1 pC over the full input signal range and typical leakage currents of 0.01 nA at 25°C.

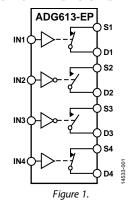
The device is fully specified for ± 5 V, 5 V, and 3 V supplies. It contains four independent single-pole, single-throw (SPST) switches. The ADG613-EP contains two switches with digital control logic that turns on with logic low and two switches in which the logic is inverted.

Each switch conducts equally well in both directions when on and has an input signal range that extends to the supplies. The

Rev. A

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FUNCTIONAL BLOCK DIAGRAM



ADG613-EP exhibits break-before-make switching action.

The ADG613-EP is available in a small, 16-lead TSSOP package.

The ADG613-EP is also a TTL-compatible device.

Additional application and technical information can be found in the ADG613 data sheet.

PRODUCT HIGHLIGHTS

- 1. Ultralow charge injection (1 pC typically).
- 2. Dual ± 2.7 V to ± 5.5 V or single 2.7 V to 5.5 V operation.
- 3. Temperature range: -55°C to +125°C.
- 4. Small, 16-lead TSSOP.

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REVISION HISTORY

10/2016—Rev. 0 to Rev. A

6/2016—Revision 0: Initial Revision

SPECIFICATIONS

DUAL-SUPPLY OPERATION

 $V_{DD} = 5~V~\pm~10\%, V_{SS} = -5~V~\pm~10\%, GND = 0~V, unless otherwise~noted.~V_{S}~is~the~source~voltage.~V_{D}~is~the~drain~voltage.$

Table 1.

Parameter	25°C	-55°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH				
Analog Signal Range		V_{SS} to V_{DD}	V	
On Resistance, R _{ON}	85		Ω typ	$V_s = \pm 3 \text{ V}, I_s = -1 \text{ mA}$; see Figure 14
	115	160	Ω max	$V_s = \pm 3 \text{ V}, I_s = -1 \text{ mA}$; see Figure 14
On-Resistance Match Between Channels, ΔR_{on}	2		Ω typ	$V_s = \pm 3 \text{ V, } I_s = -1 \text{ mA}$
	4	6.5	Ω max	$V_s = \pm 3 \text{ V, } I_s = -1 \text{ mA}$
On-Resistance Flatness, R _{FLAT(ON)}	25		Ω typ	$V_s = \pm 3 \text{ V, } I_s = -1 \text{ mA}$
	40	60	Ω max	$V_s = \pm 3 \text{ V}, I_s = -1 \text{ mA}$
LEAKAGE CURRENTS				$V_{DD} = +5.5 \text{ V}, V_{SS} = -5.5 \text{ V}$
Source Off Leakage, I _{S(OFF)}	±0.01		nA typ	$V_D = \pm 4.5 \text{ V}, V_S = \mp 4.5 \text{ V}; \text{ see Figure 15}$
	±0.1	±2	nA max	$V_D = \pm 4.5 \text{ V}, V_S = \pm 4.5 \text{ V}; \text{ see Figure 15}$
Drain Off Leakage, I _{D(OFF)}	±0.01		nA typ	$V_D = \pm 4.5 \text{ V}, V_S = \mp 4.5 \text{ V}; \text{ see Figure 15}$
5 - 7 - 5 - 7 - 7 - 7 - 7 - 7 - 7 - 7 -	±0.1	±2	nA max	$V_D = \pm 4.5 \text{ V}, V_S = \mp 4.5 \text{ V}; \text{ see Figure 15}$
Channel On Leakage, I _{D(ON)} , I _{S(ON)}	±0.01		nA typ	$V_D = V_S = \pm 4.5 \text{ V}$; see Figure 16
Chairle On Leakage, ID(ON), IS(ON)	±0.01	±6	nA max	$V_D = V_S = \pm 4.5$ V; see Figure 16
DIGITAL INPUTS	±0.1	±0	IIA IIIax	$V_0 = V_S = \pm 4.5$ V, see Figure 10
Input High Voltage, V _{NH}		2.4	V min	
Input Low Voltage, V _{NL}		0.8	V max	
Input Current, I _{NL} or I _{NH}	0.005	0.0	μA typ	$V_{IN} = V_{INI}$ or V_{INH}
input current, int or inh	0.003	±0.1	μΑ typ μΑ max	$V_{\text{IN}} = V_{\text{INI}} \text{ or } V_{\text{INH}}$
Digital Input Capacitance, C _N	2	±0.1	1 '	VIN — VINL OI VINH
DYNAMIC CHARACTERISTICS ¹	2		pF typ	
	45		ns tun	D = 2000 C = 25 pF V = 2 0 V see Figure 17
Delay from Digital Control Input and Output Switching On, t_{ON}	45		ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{pF}$, $V_S = 3.0 \text{V}$; see Figure 17
SWITCHING STI, TON	65	90	ns max	$R_L = 300 \Omega$, $C_L = 35 \text{pF}$, $V_S = 3.0 \text{V}$; see Figure 17
Delay from Digital Control Input and Output	25		ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{pF}$, $V_S = 3.0 \text{V}$; see Figure 17
Switching Off, t _{OFF}			113 () [11. 30014 et 33 pri vis 3.0 visee rigare ri
	40	50	ns max	$R_L = 300 \Omega$, $C_L = 35 \text{pF}$, $V_S = 3.0 \text{V}$; see Figure 17
Break-Before-Make Time Delay, t _{BBM}	15		ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{pF}$, $V_{S1} = V_{S2} = 3.0 \text{V}$; see Figure 18
7		10	ns min	$R_L = 300 \Omega$, $C_L = 35 \text{pF}$, $V_{S1} = V_{S2} = 3.0 \text{V}$; see Figure 18
Charge Injection	-0.5		pC typ	$V_s = 0 \text{ V, } R_s = 0 \Omega, C_L = 1 \text{ nF; see Figure 19}$
Off Isolation	-65		dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$; see Figure 20
Channel to Channel Crosstalk	-90		dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$; see Figure 21
−3 dB Bandwidth	680		MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; see Figure 22
Off Switch Source Capacitance, C _{S(OFF)}	5		pF typ	f= 1 MHz
Off Switch Drain Capacitance, C _{D(OFF)}	5		pF typ	f= 1 MHz
On Switch Capacitance, C _{D(ON)} , C _{S(ON)}	5		pF typ	f= 1 MHz
POWER REQUIREMENTS			· /·	$V_{DD} = +5.5 \text{ V}, V_{SS} = -5.5 \text{ V}$
Positive Supply Current, I _{DD}	0.001		μA typ	Digital inputs = 0 V or 5.5 V
1.1. /	1	1.0	μA max	Digital inputs = 0 V or 5.5 V
Negative Supply Current, Iss	0.001		μΑ typ	Digital inputs = 0 V or 5.5 V
· 2. ····		1.0	μA max	Digital inputs = 0 V or 5.5 V
V_{DD}/V_{SS}		±2.7	V min	bigital inputs of orsis v
• יטט		±5.5	V max	
Power Consumption	11	1	nW typ	
	11		μW max	

¹ Guaranteed by design; not subject to production test.

SINGLE-SUPPLY OPERATION

 $V_{DD} = 5 \ V \pm 10\%, V_{SS} = 0 \ V, \ GND = 0 \ V, \ unless \ otherwise \ noted. \ V_S \ is \ the \ source \ voltage. \ V_D \ is \ the \ drain \ voltage.$

Table 2.

Parameter	25°C	-55°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH				
Analog Signal Range		$0 \text{ to } V_{DD}$	V	
On Resistance, R _{ON}	210		Ωtyp	$V_S = 3.5 \text{ V}, I_S = -1 \text{ mA}$; see Figure 14
	290	380	Ω max	$V_S = 3.5 \text{ V}, I_S = -1 \text{ mA}$; see Figure 14
On-Resistance Match Between Channels, ΔR_{ON}	3		Ωtyp	$V_S = 3.5 \text{ V, } I_S = -1 \text{ mA}$
	10	13	Ω max	$V_S = 3.5 \text{ V}, I_S = -1 \text{ mA}$
LEAKAGE CURRENTS				$V_{DD} = 5.5 \text{ V}$
Source Off Leakage, I _{S(OFF)}	±0.01		nA typ	$V_S = 1 \text{ V or } 4.5 \text{ V, } V_D = 4.5 \text{ V or } 1 \text{ V; see Figure } 15$
	±0.1	±2	nA max	$V_S = 1 \text{ V or } 4.5 \text{ V}, V_D = 4.5 \text{ V or } 1 \text{ V}; \text{see Figure } 15$
Drain Off Leakage, I _{D(OFF)}	±0.01		nA typ	$V_S = 1 \text{ V or } 4.5 \text{ V, } V_D = 4.5 \text{ V or } 1 \text{ V; see Figure } 15$
	±0.1	±2	nA max	$V_S = 1 \text{ V or } 4.5 \text{ V, } V_D = 4.5 \text{ V or } 1 \text{ V; see Figure } 15$
Channel On Leakage, I _{D(ON)} , I _{S(ON)}	±0.01		nA typ	$V_S = V_D = 1 \text{ V or } 4.5 \text{ V}; \text{ see Figure } 16$
- 3 - 7 - 5 (5.1.7) - 5 (5.1.7)	±0.1	±6	nA max	$V_S = V_D = 1 \text{ V or } 4.5 \text{ V; see Figure } 16$
DIGITAL INPUTS				
Input High Voltage, V _{INH}		2.4	V min	
Input Low Voltage, V _{INL}		0.8	V max	
Input Current, I _{INL} or I _{INH}	0.005		μΑ typ	$V_{IN} = V_{INI}$ or V_{INH}
		±0.1	μA max	$V_{IN} = V_{INI}$ or V_{INH}
Digital Input Capacitance, C _{IN}	2		pF typ	
DYNAMIC CHARACTERISTICS ¹			, ,,	
ton	70		ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$, $V_S = 3.0 V$; see Figure 17
	100	150	ns max	$R_L = 300 \Omega$, $C_L = 35 \text{pF}$, $V_S = 3.0 \text{V}$; see Figure 17
toff	25		ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{pF}$, $V_S = 3.0 \text{V}$; see Figure 17
	40	50	ns max	$R_L = 300 \Omega$, $C_L = 35 \text{pF}$, $V_S = 3.0 \text{V}$; see Figure 17
Break-Before-Make Time Delay, t _{BBM}	25		ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$, $V_{S1} = V_{S2} = 3.0 V$; see Figure 18
,		10	ns min	$R_L = 300 \Omega$, $C_L = 35 pF$, $V_{S1} = V_{S2} = 3.0 V$; see Figure 18
Charge Injection	1		pC typ	$V_S = 0 \text{ V}, R_S = 0 \Omega, C_L = 1 \text{ nF}; \text{ see Figure 19}$
Off Isolation	-62		dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$; see Figure 20
Channel to Channel Crosstalk	-90		dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$; see Figure 21
–3 dB Bandwidth	680		MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; see Figure 22
C _{S(OFF)}	5		pF typ	f = 1 MHz
C _D (OFF)	5		pF typ	f = 1 MHz
C _D (ON), C _S (ON)	5		pF typ	f = 1 MHz
POWER REQUIREMENTS			1 71	V _{DD} = 5.5 V
I _{DD}	0.001		μA typ	Digital inputs = 0 V or 5.5 V
		1.0	μA max	Digital inputs = 0 V or 5.5 V
V_{DD}		2.7	V min	- 5
		5.5	V max	
Power Consumption	5.5		nW typ	
	5.5		μW max	

 $^{^{\}rm 1}\,\mbox{Guaranteed}$ by design; not subject to production test.

 V_{DD} = 3 V \pm 10%, V_{SS} = 0 V, GND = 0 V, unless otherwise noted. V_{S} is the source voltage. V_{D} is the drain voltage.

Table 3.

Parameter	25°C	-55°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH				
Analog Signal Range		0 to V_{DD}	V	
On Resistance, R _{ON}	380	460	Ωtyp	$V_S = 1.5 \text{ V}, I_S = -1 \text{ mA}$; see Figure 14
LEAKAGE CURRENTS				$V_{DD} = 3.3 \text{ V}$
Source Off Leakage, I _{S(OFF)}	±0.01		nA typ	$V_S = 1 \text{ V or } 3 \text{ V, } V_D = 3 \text{ V or } 1 \text{ V; see Figure } 15$
	±0.1	±2	nA max	$V_S = 1 \text{ V or } 3 \text{ V, } V_D = 3 \text{ V or } 1 \text{ V; see Figure } 15$
Drain Off Leakage, I _{D(OFF)}	±0.01		nA typ	$V_S = 1 \text{ V or } 3 \text{ V}, V_D = 3 \text{ V or } 1 \text{ V}; \text{ see Figure } 15$
	±0.1	±2	nA max	$V_S = 1 \text{ V or } 3 \text{ V, } V_D = 3 \text{ V or } 1 \text{ V; see Figure } 15$
Channel On Leakage, ID(ON), IS(ON)	±0.01		nA typ	$V_S = V_D = 1 \text{ V or } 3 \text{ V; see Figure } 16$
	±0.1	±6	nA max	$V_S = V_D = 1 \text{ V or } 3 \text{ V; see Figure } 16$
DIGITAL INPUTS			İ	
Input High Voltage, V _{INH}		2.0	V min	
Input Low Voltage, VINL		0.8	V max	
Input Current, I _{INL} or I _{INH}	0.005		μA typ	$V_{IN} = V_{INL} \text{ or } V_{INH}$
		±0.1	μA max	$V_{IN} = V_{INL} \text{ or } V_{INH}$
Digital Input Capacitance, C _{IN}	2		pF typ	
DYNAMIC CHARACTERISTICS ¹				
ton	130		ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$, $V_S = 2 V$; see Figure 17
	185	260	ns max	$R_L = 300 \Omega$, $C_L = 35 pF$, $V_S = 2 V$; see Figure 17
t _{OFF}	40		ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$, $V_S = 2 V$; see Figure 17
	55	65	ns max	$R_L = 300 \Omega$, $C_L = 35 pF$, $V_S = 2 V$; see Figure 17
Break-Before-Make Time Delay, t _{BBM}	50		ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$, $V_{S1} = V_{S2} = 2 V$; see Figure 18
		10	ns min	$R_L = 300 \Omega$, $C_L = 35 pF$, $V_{S1} = V_{S2} = 2 V$; see Figure 18
Charge Injection	1.5		pC typ	$V_S = 0 \text{ V, } R_S = 0 \Omega, C_L = 1 \text{ nF; see Figure 19}$
Off Isolation	-62		dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$; see Figure 20
Channel to Channel Crosstalk	-90		dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$; see Figure 21
–3 dB Bandwidth	680		MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; see Figure 22
C _{S(OFF)}	5		pF typ	f = 1 MHz
$C_D(OFF)$	5		pF typ	f = 1 MHz
$C_{D(ON)}$, $C_{S(ON)}$	5		pF typ	f = 1 MHz
POWER REQUIREMENTS				$V_{DD} = 3.3 \text{ V}$
I_{DD}	0.001		μA typ	Digital inputs = 0 V or 3.3 V
		1.0	μA max	Digital inputs = 0 V or 3.3 V
V_{DD}		2.7	V min	
		5.5	V max	
Power Consumption	3.3		nW typ	
•	3.3		μW max	

¹ Guaranteed by design; not subject to production test.

ABSOLUTE MAXIMUM RATINGS

 $T_A = 25$ °C, unless otherwise noted

Table 4.

Table 4.					
Parameter	Rating				
V _{DD} to V _{SS} ¹	13 V				
V_{DD} to GND^1	−0.3 V to +6.5 V				
V _{SS} to GND ¹	+0.3 V to -6.5 V				
Analog Inputs ²	$V_{SS} - 0.3 V to V_{DD} + 0.3 V$				
Digital Inputs ²	GND -0.3 V to $V_{DD} + 0.3$ V or 30 mA, whichever occurs first				
Peak Current, Sx or Dx	20 mA (pulsed at 1 ms, 10% duty cycle maximum)				
Continuous Current, Sx or Dx	10 mA				
3 V Operation, 85°C to 125°C	7.5 mA				
Operating Temperature Range	–55℃ to +125℃				
Storage Temperature Range	–65℃ to +150℃				
Junction Temperature	150℃				
θ_{JA} Thermal Impedance					
16-Lead TSSOP	150.4℃/W				
Lead Soldering					
Lead Temperature, Soldering (10 sec)	300℃				
IR Reflow, Peak Temperature (<20 sec)	220℃				
Pb-Free Soldering					
Reflow, Peak Temperature	260 (+0/−5)℃				
Time at Peak Temperature	20 sec to 40 sec				

 $^{^{1}}$ Tested at -55° C to $+125^{\circ}$ C.

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

Only one absolute maximum rating can be applied at any one time.

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

 $^{^2}$ Overvoltages at INx, Sx, or Dx are clamped by internal diodes. Limit the current to the maximum ratings given. Tested at -55°C to +125°C.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

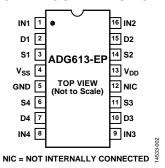


Figure 2. Pin Configuration

Table 5. Pin Function Descriptions

Pin No.	Mnemonic	Description			
1	IN1	Switch 1 Digital Control Input.			
2	D1	Drain Terminal of Switch 1. This pin can be an input or output.			
3	S1	Source Terminal of Switch 1. This pin can be an input or output.			
4	V_{SS}	Most Negative Power Supply Terminal. Tie this pin to GND when using the device with single-supply voltages.			
5	GND	Ground (0 V) Reference.			
6	S4	Source Terminal of Switch 4. This pin can be an input or output.			
7	D4	Drain Terminal of Switch 4. This pin can be an input or output.			
8	IN4	witch 4 Digital Control Input.			
9	IN3	Switch 3 Digital Control Input.			
10	D3	Drain Terminal of Switch 3. This pin can be an input or output.			
11	S3	Source Terminal of Switch 3. This pin can be an input or output.			
12	NIC	Not Internally Connected.			
13	V_{DD}	Most Positive Power Supply Terminal.			
14	S2	Source Terminal of Switch 2. This pin can be an input or output.			
15	D2	Drain Terminal of Switch 2. This pin can be an input or output.			
16	IN2	Switch 2 Digital Control Input.			

Table 6. Truth Table

Logic	S1 and S4	S2 and S3
0	Off	On
1	On	Off

TYPICAL PERFORMANCE CHARACTERISTICS

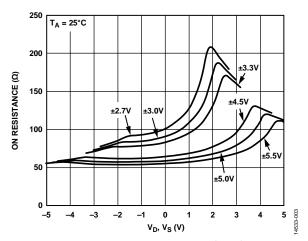


Figure 3. On Resistance vs. V_D, V_S; Dual Supplies

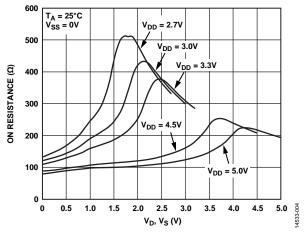


Figure 4. On Resistance vs. V_D, V_S; Single Supply

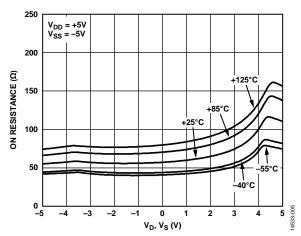


Figure 5. On Resistance vs. V_D , V_S for Various Temperatures, Dual Supplies

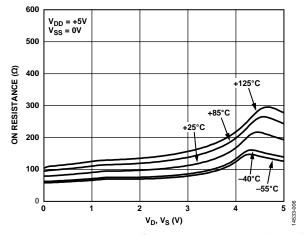


Figure 6. On Resistance vs. V_D , V_S for Various Temperatures, Single Supply

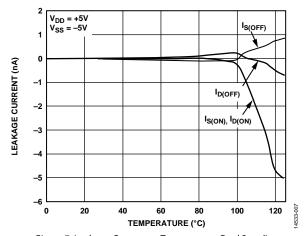


Figure 7. Leakage Current vs. Temperature, Dual Supplies

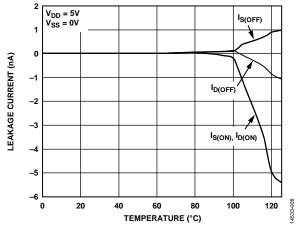


Figure 8. Leakage Current vs. Temperature, Single Supply

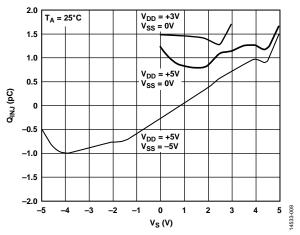


Figure 9. Charge Injection (Q_{INJ}) vs. Source Voltage (V_S)

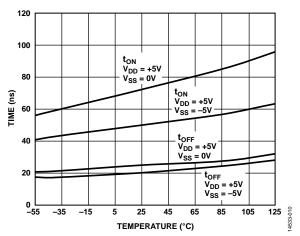


Figure 10. t_{ON}/t_{OFF} Times vs. Temperature

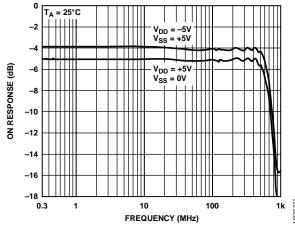


Figure 11. On Response vs. Frequency

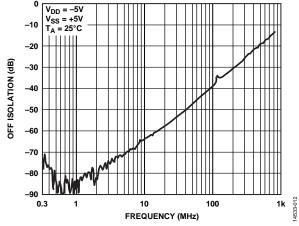


Figure 12. Off Isolation vs. Frequency

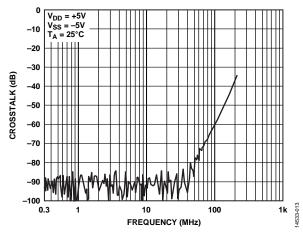


Figure 13. Crosstalk vs. Frequency

TEST CIRCUITS

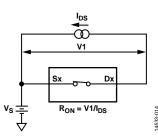
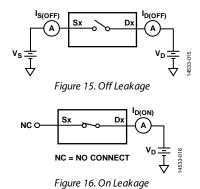


Figure 14. On Resistance



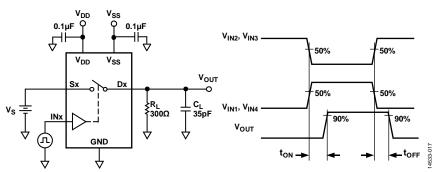


Figure 17. Switching Times

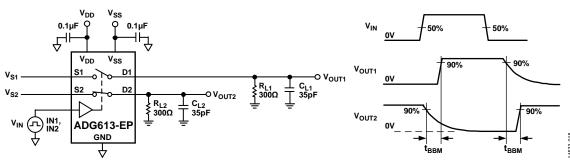


Figure 18. Break-Before-Make Time Delay

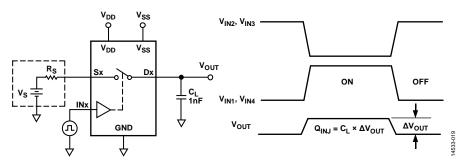


Figure 19. Charge Injection

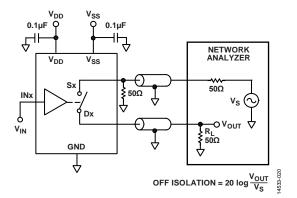


Figure 20. Off Isolation

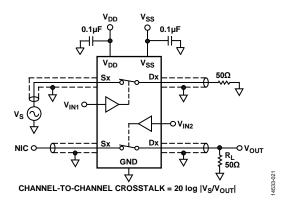


Figure 21. Channel-to-Channel Crosstalk

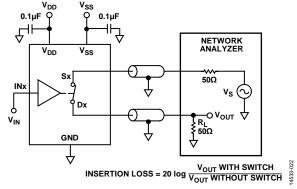
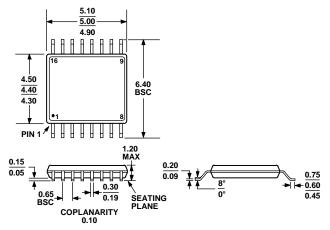


Figure 22. Bandwidth

OUTLINE DIMENSIONS



COMPLIANT TO JEDEC STANDARDS MO-153-AB

Figure 23. 16-Lead Thin Shrink Small Outline Package [TSSOP] (RU-16) Dimensions shown in millimeters

ORDERING GUIDE

Model ¹	Temperature Range	Package Description	Package Option
ADG613SRUZ-EP	–55℃ to +125℃	16-Lead Thin Shrink Small Outline Package [TSSOP]	RU-16
ADG613SRUZ-EP-RL7	–55℃ to +125℃	16-Lead Thin Shrink Small Outline Package [TSSOP]	RU-16

 $^{^{1}}$ Z = RoHS Compliant Part.



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